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(12) **United States Design Patent**  
**Saito et al.**

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(54) **CHAMBER OF CHARGED PARTICLE BEAM DRAWING APPARATUS**

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(\*\*) Term: **14 Years**

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**Related U.S. Application Data**

(63) Continuation-in-part of application No. 29/479,498, filed on Jan. 16, 2014, now Pat. No. Des. 722,298.

**Foreign Application Priority Data**

Jul. 17, 2013 (JP) ..... 2013-016242

(51) **LOC (10) Cl.** ..... **13-03**

(52) **U.S. Cl.**  
USPC ..... **D13/182**

(58) **Field of Classification Search**

USPC ..... D13/101, 123, 182; 250/396 R, 396 ML, 250/398, 400, 492.1, 492.2, 492.21, 492.22, 250/492.3; 430/4, 5, 24, 25, 30, 269, 396  
CPC ... H01J 37/153; H01J 37/141; H01J 37/3174; H01J 37/3175; H01J 37/12; H01J 37/045; H01J 37/3007; H01J 2237/31715; H01J 2237/31752; G21K 1/08; G21K 1/087; G21K 1/093; G21K 5/04; G21K 5/10; G21K 2201/00; G21K 2201/068; B29C 67/0066  
See application file for complete search history.

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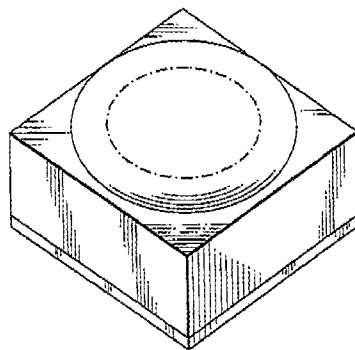
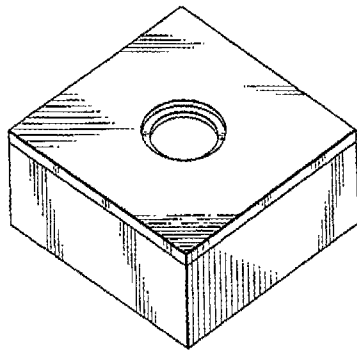
(57) **CLAIM**

The ornamental design for a chamber of charged particle beam drawing apparatus, as shown and described.

**DESCRIPTION**

FIG. 1 is a top perspective view of a chamber of charged particle beam drawing apparatus showing our new design; FIG. 2 is a bottom perspective view thereof; FIG. 3 is a front view thereof; FIG. 4 is a right side view thereof, the left side view being a mirror image; FIG. 5 is a top plan view thereof; FIG. 6 is a bottom plan view thereof; FIG. 7 is a cross-sectional view taken along a line 7-7 in FIG. 3; and, FIG. 8 is a cross-sectional view taken along a line 8-8 in FIG. 3.  
The dot-dash lines indicate the boundary between the claimed portion and unclaimed portion.

**1 Claim, 4 Drawing Sheets**



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			H01J 37/317					
			250/492.3					

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FIG. 1

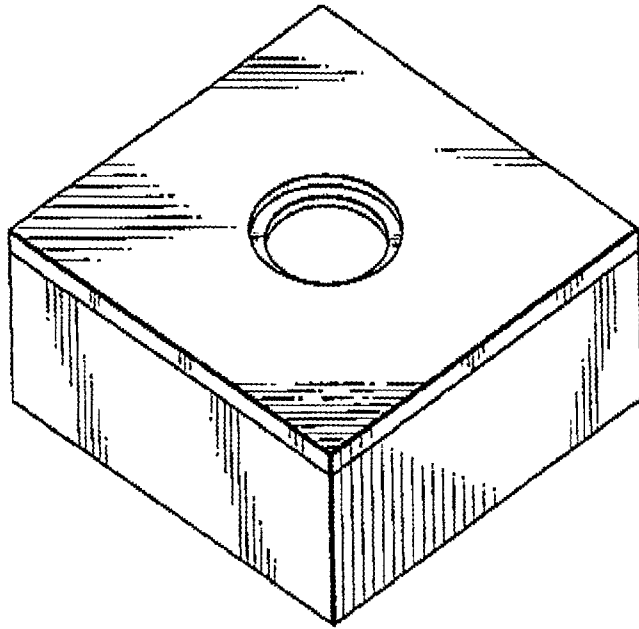


FIG. 2

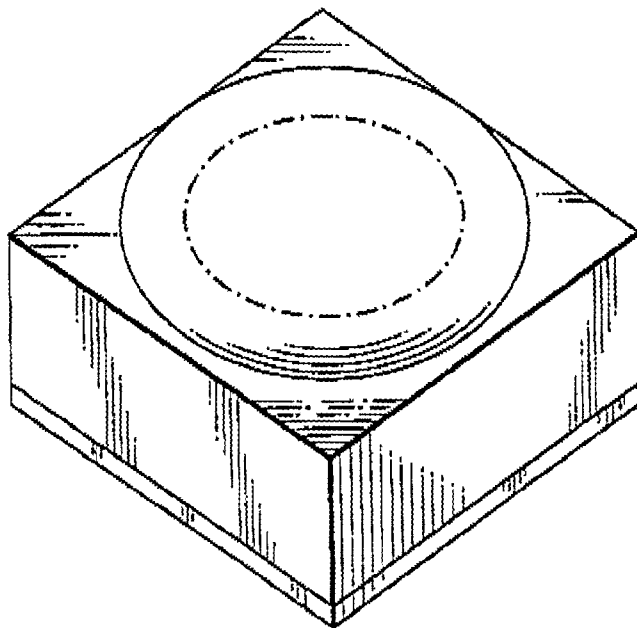


FIG. 3

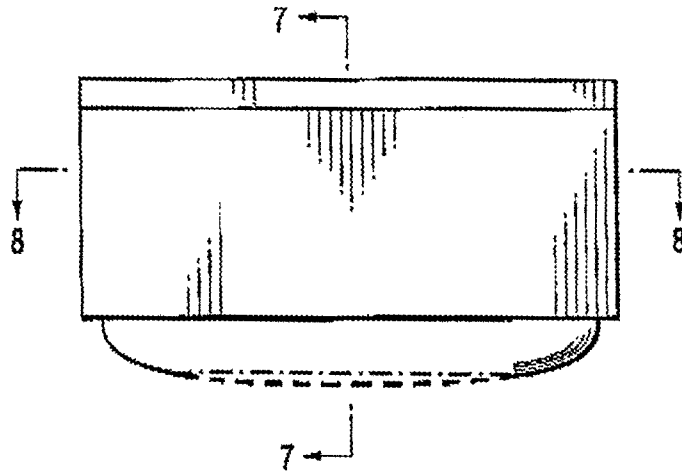


FIG. 4

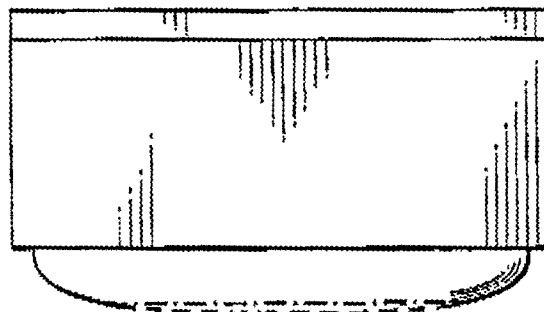


FIG. 5

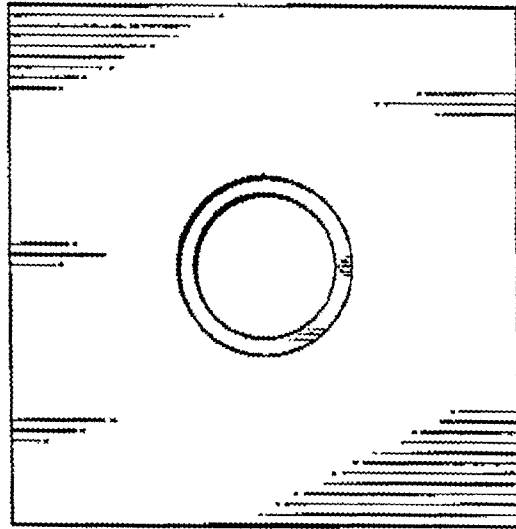


FIG. 6

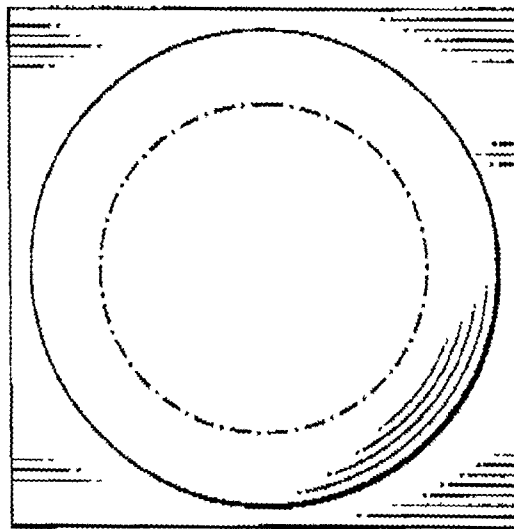


FIG. 7

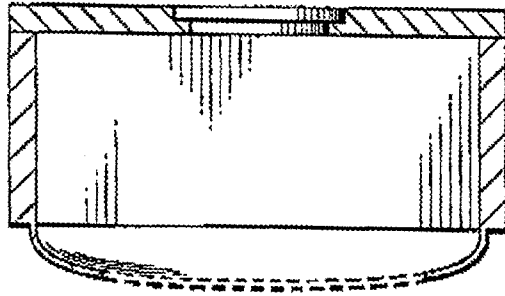


FIG. 8

